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Submicron-Resolution Texture and Strain Determination Using X-ray Microbeams

J. D. Budai, B.C. Larson, G.E. Ice, J.Z. Tischler, W. Yang, K.-S. Chung, and D.P. Norton

Solid State Division
Oak Ridge National Laboratory
Oak Ridge, Tennessee 37831-6030

and

W.P. Lowe
Howard University

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